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That broad line, those advanced technologies, are what you'd expect from those who introduced the first Windows-operated TEM and who've made TEMs since 1941, SEMs since 1969, FE-SEMs since 1972 and FE-TEMs since 1983. We're also the company that's averaged over 1000 patents a year since 1976. Further, we're the people currently pioneering interactive, Internet-based "collaboration microscopy" and a 1-MV field-emission transmission electron microscope.

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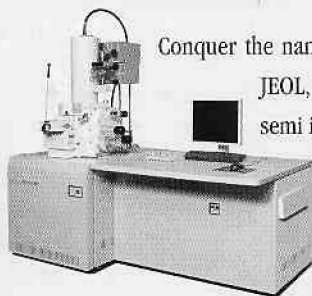
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